

# IGBT A

## A a

### 650 V, 40 A

# AFGHL40T65RQDN

Using novel field stop IGBT technology, onsemi's new series of FS4 IGBTs offer the optimum performance for automotive applications. This technology is Short circuit rated and offers high figure of merit with low conduction and switching losses.

#### Features

- Maximum Junction Temperature:  $T_J = 175^\circ\text{C}$
- Positive Temperature Co-efficient for Easy Parallel Operation
- High Current Capability
- Low Saturation Voltage:  $V_{CE(Sat)} = 1.6\text{ V (Typ.) @ } I_C = 40\text{ A}$
- 100% of the Parts Tested for  $I_{LM}$  (Note 2)
- High Input Impedance
- Fast Switching
- Tightened Parameter Distribution
- This Device is Pb-Free and RoHS Compliant

#### Typical Applications

- E-compressor for HEV/EV, PTC heater for HEV/EV

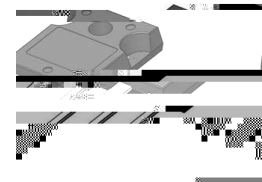
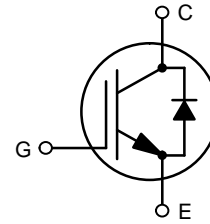
#### MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-to-Emitter Voltage	$V_{CES}$	650	V
Gate-to-Emitter Voltage Transient Gate-to-Emitter Voltage	$V_{GES}$	$\pm 20$ $\pm 30$	V
Collector Current (Note 1) @ $T_C = 25^\circ\text{C}$ @ $T_C = 100^\circ\text{C}$	$I_C$	46 40	A
Pulsed Collector Current (Note 2)	$I_{LM}$	160	A
Pulsed Collector Current (Note 3)	$I_{CM}$	160	A
Diode Forward Current (Note 1) @ $T_C = 25^\circ\text{C}$ @ $T_C = 100^\circ\text{C}$	$I_F$	46 40	A
Pulsed Diode Maximum Forward Current	$I_{FM}$	160	A
Non-Repetitive Forward Surge Current (Half-Sine Pulse, $t_p = 8.3\text{ ms}$ , $T_C = 25^\circ\text{C}$ ) (Half-Sine Pulse, $t_p = 8.3\text{ ms}$ , $T_C = 150^\circ\text{C}$ )	$I_{FM}$	170 150	A
Short Circuit Withstand Time $V_{GE} = 15\text{ V}$ , $V_{CC} = 400\text{ V}$ , $T_C = 150^\circ\text{C}$	$t_{SC}$	5	$\mu\text{s}$
Maximum Power Dissipation @ $T_C = 25^\circ\text{C}$ @ $T_C = 100^\circ\text{C}$	$P_D$	288 144	W
Operating Junction/Storage Temperature Range	$T_J, T_{STG}$	-55 to +175	$^\circ\text{C}$
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	$T_L$	265	$^\circ\text{C}$

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Value limited by bond wire.
2.  $V_{CC} = 600\text{ V}$ ,  $V_{GE} = 15\text{ V}$ ,  $I_C = 120\text{ A}$ ,  $R_G = 67\ \Omega$ , Inductive Load, 100% Tested.
3. Repetitive Rating: pulse width limited by max. Junction temperature.

40 A, 650 V,  
 $V_{CE(Sat)} = 1.6\text{ V (Typ.)}$



TO-247-3L  
CASE 340CX

#### MARKING DIAGRAM



A = Assembly Site  
WW = Work Week Number  
Y = Year of Production,  
Last Number  
ZZ = Assembly Lot Number  
AFGHL40T65RQDN = Specific Device Code

#### ORDERING INFORMATION

Device	Package	Shipping
AFGHL40T65RQDN	TO-247-3L (Pb-Free)	30 Units / Rail

# AFGHL40T65RQDN

## THEMAL CHARACTERISTICS

Rating	Symbol	Min	Typ	Max	Unit
Thermal Resistance Junction-to-Case, for IGBT	$R_{\theta JC}$	-	0.40	0.52	°C/W
Thermal Resistance Junction-to-Case, for Diode	$R_{\theta JC}$	-	0.86	1.12	
Thermal Resistance Junction-to-Ambient	$R_{\theta JA}$	-	-	40	

## ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Test Conditions	Symbol	Min	Typ	Max	Unit
-----------	-----------------	--------	-----	-----	-----	------

### OFF CHARACTERISTICS

Collector-emitter Breakdown Voltage, Gate-emitter Short-circuited	$V_{GE} = 0\text{ V}, I_C = 1\text{ mA}$	$BV_{CES}$	650	-	-	V
Temperature Coefficient of Breakdown Voltage	$V_{GE} = 0\text{ V}, I_C = 1\text{ mA}$	$\frac{\Delta BV_{CES}}{\Delta T_J}$	-	0.50	-	V/°C
Collector-emitter Cut-off Current, Gate-emitter Short-circuited	$V_{GE} = 0\text{ V}, V_{CE} = V_{CES}$	$I_{CES}$	-	-	30	μA
Gate Leakage Current, Collector-emitter Short-circuited	$V_{GE} = V_{GES}, V_{CE} = 0\text{ V}$	$I_{GES}$	-	-	±400	nA

### ON CHARACTERISTICS

Gate-emitter Threshold Voltage	$V_{GE} = V_{CE}, I_C = 40\text{ mA}$	$V_{GE(th)}$	3.75	4.90	6.05	V
Collector-emitter Saturation Voltage	$V_{GE} = 15\text{ V}, I_C = 40\text{ A}, T_J = 25^\circ\text{C}$ $V_{GE} = 15\text{ V}, I_C = 40\text{ A}, T_J = 175^\circ\text{C}$	$V_{CE(sat)}$	-	1.6	1.82	V
			-	1.96	-	

### DYNAMIC CHARACTERISTICS

Input Capacitance	$V_{CE} = 30\text{ V}, V_{GE} = 0\text{ V}, f = 1\text{ MHz}$	$C_{ies}$	-	2053	-	pF
Output Capacitance		$C_{oes}$	-	73	-	
Reverse Transfer Capacitance		$C_{res}$	-	9	-	
Gate Resistance	$f = 1\text{ MHz}$	$R_g$	-	16.5	-	Ω
Gate Charge Total	$V_{CC} = 400\text{ V}, I_C = 40\text{ A}, V$					

# AFGHL40T65RQDN

## ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ unless otherwise noted) (Continued)

Parameter	Test Conditions	Symbol	Min	Typ	Max	Unit
-----------	-----------------	--------	-----	-----	-----	------

### SWITCHING CHARACTERISTICS, INDUCTIVE LOAD

Turn-on Delay Time	$T_J = 175^\circ\text{C}, V_{CC} = 400\text{ V},$ $I_C = 20\text{ A}, R_G = 2.5\ \Omega,$ $V_{GE} = 15\text{ V},$ Inductive Load	$t_{d(on)}$	-	24	-	ns
Rise Time		$t_r$	-	28	-	
Turn-off Delay Time		$t_{d(off)}$	-	112	-	
Fall Time		$t_f$	-	184	-	
Turn-on Switching Loss		$E_{on}$	-	0.74	-	mJ
Turn-off Switching Loss		$E_{off}$	-	0.93	-	
Total Switching Loss		$E_{ts}$	-	1.67	-	
Turn-on Delay Time	$T_J = 175^\circ\text{C}, V_{CC} = 400\text{ V},$ $I_C = 40\text{ A}, R_G = 2.5\ \Omega,$ $V_{GE} = 15\text{ V},$ Inductive Load	$t_{d(on)}$	-	26	-	ns
Rise Time		$t_r$	-	54	-	
Turn-off Delay Time		$t_{d(off)}$	-	90	-	
Fall Time		$t_f$	-	138	-	
Turn-on Switching Loss		$E_{on}$	-	1.62	-	mJ
Turn-off Switching Loss		$E_{off}$	-	1.40	-	
Total Switching Loss		$E_{ts}$	-	3.02	-	

### DIODE CHARACTERISTICS

Diode Forward Voltage	$I_F = 40\text{ A}, T_J = 25^\circ\text{C}$	$V_F$	-	1.72	2.20	V
	$I_F = 40\text{ A}, T_J = 175^\circ\text{C}$		-	1.77	-	

### DIODE SWITCHING CHARACTERISTICS, INDUCTIVE LOAD

Reverse Recovery Energy	$I_F = 40\text{ A}, dI_F/dt = 1000\text{ A}/\mu\text{s}$ $V_R = 400\text{ V}, T_J = 25^\circ\text{C}$	$E_{rec}$	-	54	-	$\mu\text{J}$
Diode Reverse Recovery Time		$T_{rr}$	-	44	-	nS
Diode Reverse Recovery Charge		$Q_{rr}$	-	416	-	nC
Reverse Recovery Energy	$I_F = 40\text{ A}, dI_F/dt = 1000\text{ A}/\mu\text{s}$ $V_R = 400\text{ V}, T_J = 175^\circ\text{C}$	$E_{rec}$	-	224	-	$\mu\text{J}$
Diode Reverse Recovery Time		$T_{rr}$	-	89	-	nS
Diode Reverse Recovery Charge		$Q_{rr}$	-	1125	-	nC

AFGHL40T65RQDN

# AFGHL40T65RQDN

## TYPICAL CHARACTERISTICS (Continued)

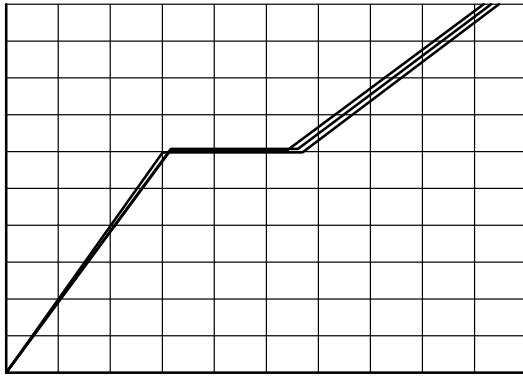


Figure 7. Gate Charge Characteristics

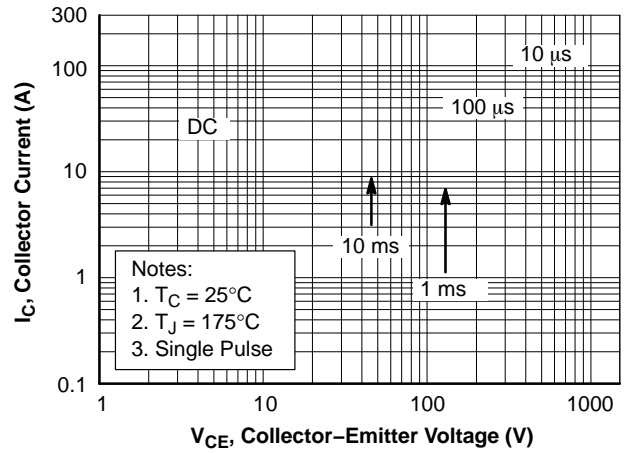


Figure 8. SOA Characteristics

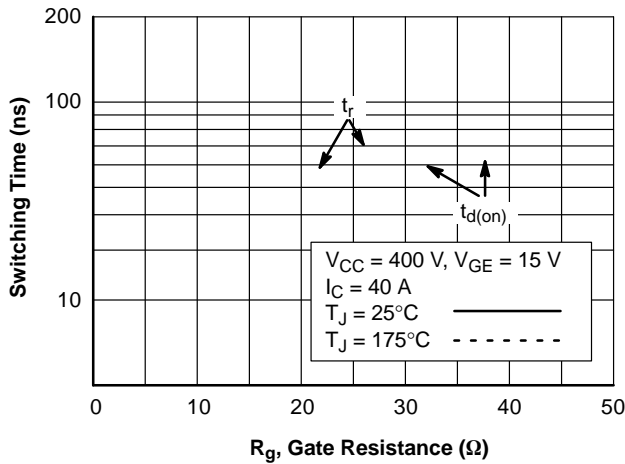


Figure 9. Turn-on Characteristics vs. Gate Resistance

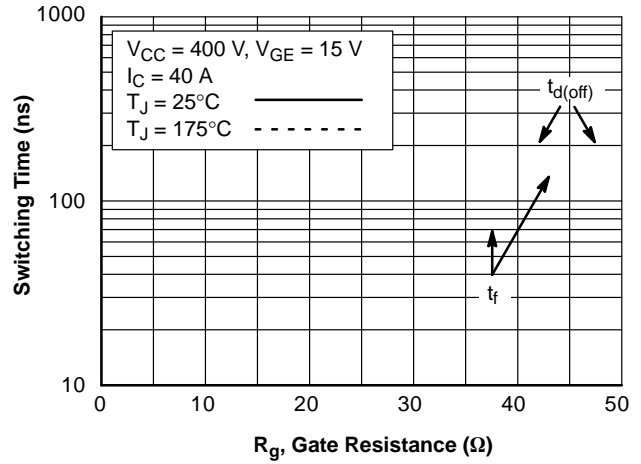


Figure 10. Turn-off Characteristics vs. Gate Resistance

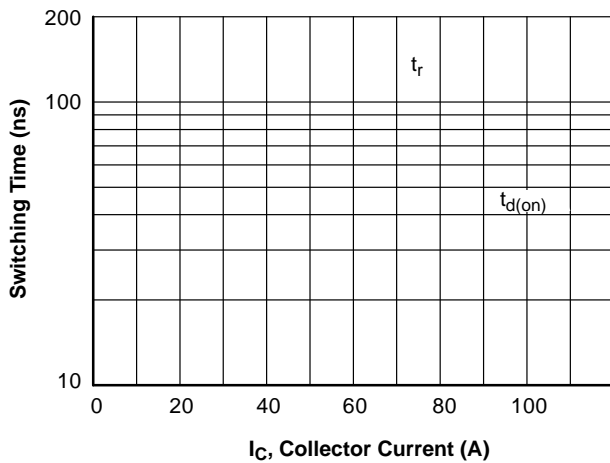


Figure 11. Turn-on Characteristics vs. Collector Current

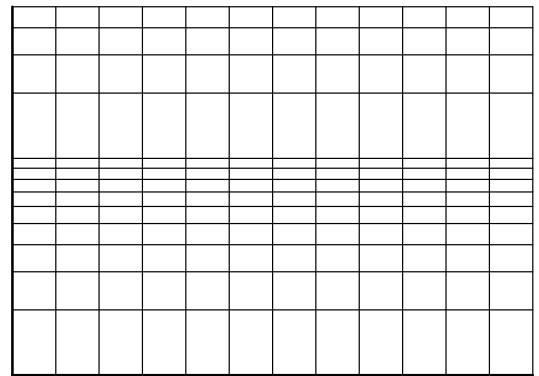
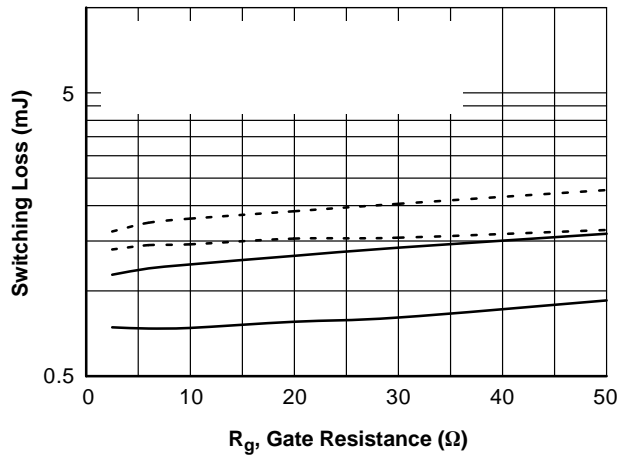


Figure 12. Turn-off Characteristics vs. Collector Current

# AFGHL40T65RQDN

## TYPICAL CHARACTERISTICS (Continued)



# AFGHL40T65RQDN

## TYPICAL CHARACTERISTICS (Continued)

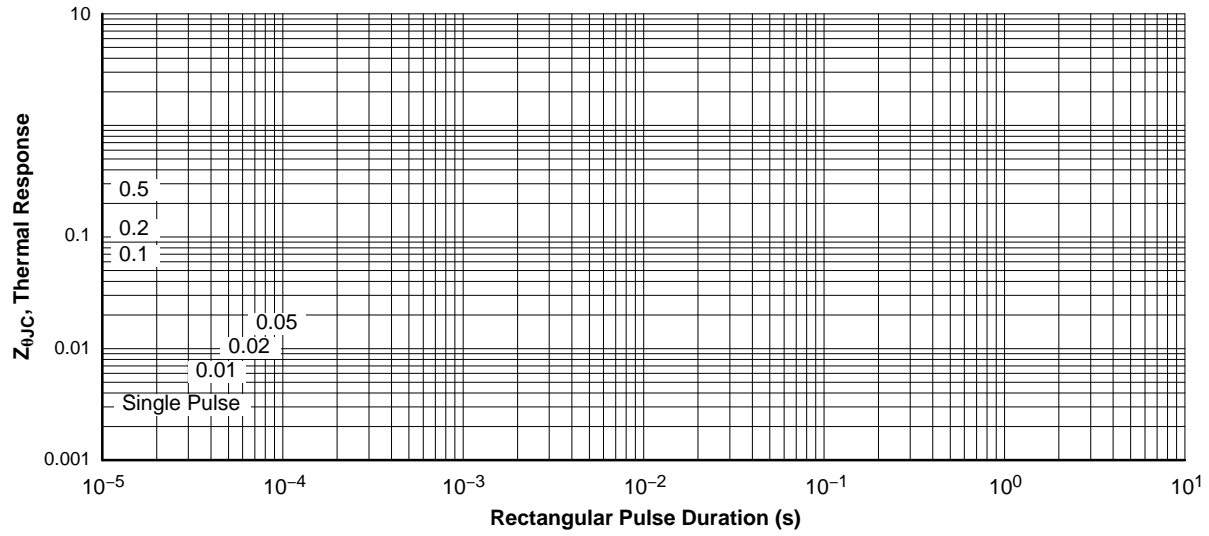


Figure 19. Transient Thermal Impedance of IGBT

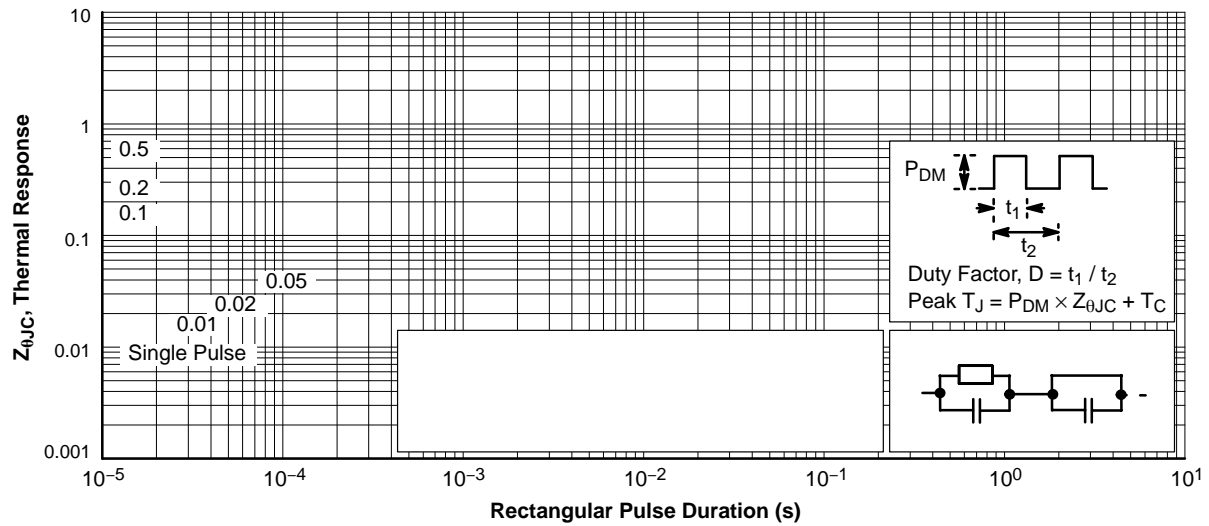


Figure 20. Transient Thermal Impedance of Diode





**onsemi**, **onsemi**, and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "**onsemi**" or its affiliates and/or subsidiaries in the United States and/or other countries. **onsemi** owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of **onsemi**'s product/patent coverage may be accessed at [www.onsemi.com/site/pdf/Patent-Marking.pdf](http://www.onsemi.com/site/pdf/Patent-Marking.pdf). **onsemi** reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and **onsemi** makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does **onsemi** assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using **onsemi**

---

---